MAX-PLANCK-GESELLSCHAFT

JEOL
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Stuttgart Atomic Resolution Microscopy Symposium

15 - 16 December 2014

StEM
Stuttgart Center for Electron Microscopy

Max Planck Institute for Intelligent Systems
Stuttgart Center
for Electron Microscopy
Heisenbergstraße 3
70569 Stuttgart
Germany

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StAR-M: Stuttgart Atomic Resolution Microscopy Symposium

The Stuttgart Center for Electron Microscopy is pleased to announce the inauguration ceremony for its two new C_s-corrected JEOL JEM-ARM200F, scheduled for 15 - 16 December 2014.

The event will be accompanied by a Symposium on Atomic Resolution Microscopy – a two-day program of invited speakers discussing the latest results and developing techniques.

Topics will include:

- quantitative analysis of lattice resolved STEM imaging and atomic resolution EELS and EDX
- guided surface plasmon excitations and coupling phenomena of plasmonic modes
- potential applications of electron vortices and energy loss magnetic chiral dichroism
- high-resolution and novel hybrid electron holography techniques
- nanostructure strain measurements and structure-property relationships at atomic scale defects
- high-resolution imaging of functionalized 2D materials
- time-resolved TEM for in-situ observation of dynamic processes

Symposium Speakers

- Philip Batson
- Gianluigi Botton
- Nigel Browning
- Rafal Dunin-Borkowski
- Joanne Etheridge
- Max Haider
- Martin Hÿtch
- Angus Kirkland
- Christoph Koch
- Mathieu Kociak
- Michael Lehmann
- Joachim Mayer
- Jannik Meyer
- Stephen Pennycook
- Quentin Ramasse
- Peter Schattschneider
- Kazu Suenaga
- Johan Verbeeck
- Masashi Watanabe

Location

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Stuttgart Center for Electron Microscopy
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70569 Stuttgart
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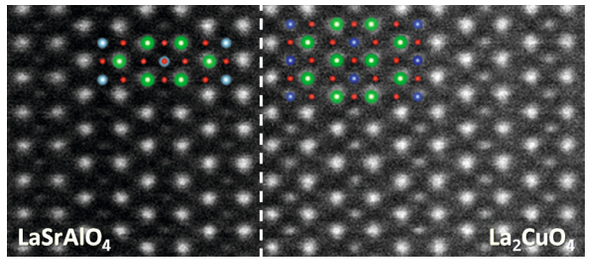

For more information:
Web: www.is.mpg.de/star-m
Email: star-m@is.mpg.de

Registration deadline: *
30 November 2014

* Register by Email or by mail, using the card enclosed.